

Interchangeable DLD 4040 IG



Interchangeable Delayline Detector for Photoemission Electronmicroscops (PEEM)

Features

- 2D detector and an electrostatic column extension on a linear feed-through for an in-situ switching between DLD and imaging unit of a PEEM
 - CF63 mounting flange
 - 40 x 40 mm² active area of DLD body and \varnothing 40 mm active MCP area
 - Linear response due to single event counting
 - Extremely low dark count rate: < 5 cps
 - Up to 3 MHz count rate in 2D mode
 - Up to 41 μ m of pixel size
 - Up to 81 ps digital time bin resolution
 - Time histogramming for time of flight (tof) measurements
 - Also available as hybrid version with an additional integrated 9 channel detector
-
- For further information contact Surface Concept GmbH



Surface Concept GmbH

Staudinger Weg 7 · 55128 Mainz
Tel.: 06131 3923632 · Fax: 0721 151468621
www.surface-concept.de